

Search Notes

Application/Control No.

10/791,815

Examiner

David Buttner

Applicant(s)/Patent under
Reexamination

FUJISAWA ET AL.

Art Unit

1712

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
524	all	5/24/2006	DB
473	all	5/24/2006	DB

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR